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Introduction

With the development of science and technology and the improvement of the requirement in machinery manufacturing, most countries in the world have put lots of human and material resources into the field of mechanical engineering precision measurement research. New methods, new technology and new equipment appear thick and fast. Under this background, we have successfully held five sessions of International Symposium on Precision Mechanical Measurement (ISPMM). The subject and the major topics include length and angular measurement, coordinate measurement technology, micro-nano metrology and MEMS, sensor technology and application, online automatic measurement and control vibration, stress and thermal measurement, opto-electronic measurement and image processing, measurement signal analysis and processing, precision theory and uncertainty evaluation, quality engineering theory and technology and so on. The 6th ISPMM conference was held in Guiyang, August 8-12, and the theme of the conference was "New century, new technology and new development." More than 150 manuscripts were submitted to our conference, and over 200 registered delegates participated in the conference.

Yetai Fei
Shenghua Ye